

Notice of References Cited	Application/Control No. 10/563,626		Applicant(s)/Patent Under Reexamination OHTSU ET AL.	
	Examiner Sang Nguyen		Art Unit 2886	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0085351	05-2003	Nakajima et al.	250/306
*	B	US-7,247,012	07-2007	Anand et al.	425/131.1
*	C	US-6,236,783	05-2001	Mononobe et al.	385/43
*	D	US-6,370,306	04-2002	Sato et al.	385/129
*	E	US-6,118,521	09-2000	Jung et al.	356/73
*	F	US-6,064,060	05-2000	Konada, Takeshi	250/234
*	G	US-5,928,525	07-1999	Ohtsu et al.	216/24
*	H	US-5,664,036	09-1997	Islam, Mohammed N.	385/31
*	I	US-5,363,463	11-1994	Kleinerman, Marcos Y.	385/123
*	J	US-5,361,314	11-1994	Kopelman et al.	385/12
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.